

**WHAT IS CLAIMED IS:**

- 1    1.    A semiconductor memory device comprising:
  - 2            an input pin row including a plurality of input
  - 3 pins;
  - 4            an output pin row including a plurality of output
  - 5 pins;
  - 6            a memory cell array including a plurality of cell
  - 7 plates in a plurality of cell columns between the input
  - 8 and output pin rows;
  - 9            a plurality of sense amplifiers in two amplifier
  - 10 columns disposed between the adjacent two of the
  - 11 plurality of cell columns;
  - 12            an address circuitry;
  - 13            an address transition detector (ATD) circuitry to
  - 14 provide an ATD pulse upon detecting a transition in the
  - 15 address circuitry;
  - 16            an ATD pulse synthesizer to provide a synthesized
  - 17 pulse in response to the ATD pulse;
  - 18            an output circuitry; and
  - 19            a delay circuitry to provide a sense amplifier data
  - 20 latch signal and an output data latch signal in response
  - 21 to the synthesized pulse from the ATD pulse synthesizer,
  - 22            at least the address, ATD and delay circuitries
  - 23 being disposed between the input pin row and the
  - 24 plurality of cell columns,
  - 25            the ATD pulse synthesizer being disposed between
  - 26 the two amplifier columns and spaced a predetermined
  - 27 signal transmission path from the ATD and delay
  - 28 circuitries.
- 1    2.    The semiconductor memory device as claimed in claim
- 2    1, further comprising:
- 3            an error correction code (ECC) circuitry disposed

4 between the two amplifier columns together with the ATD  
5 pulse synthesizer, and the delay circuitry provides an  
6 ECC data latch signal.

1 3. The semiconductor memory device as claimed in claim  
2 1 or 2, wherein said output circuitry is disposed between  
3 the two amplifier columns and between the ATD pulse  
4 synthesizer and the output pin row.

1 4. The semiconductor memory device as claimed in claim  
2 1 or 2, wherein said output circuitry is disposed between  
3 the cell columns and the output pin row.

1 5. The semiconductor memory device as claimed in claim  
2 1 or 2, wherein the device has write function.

1 6. The semiconductor memory device as claimed in claim  
2 1 or 2, wherein the address, ATD and delay circuitries  
3 only are disposed in a site between the input pin row and  
4 the plurality of cell columns.

1 7. The semiconductor memory device as claimed in claim  
2 1 or 2, wherein the number of the plurality of cell plates  
3 is four.

1 8. The semiconductor memory device as claimed in claim  
2 1 or 2, wherein the output pin row includes at least one  
3 input pin.

1 9. The semiconductor memory device as claimed in claim  
2 1 or 2,  
3 wherein each of the plurality of cell columns  
4 include a plurality pairs of cell plates, and  
5 further comprising:

6       a plurality of X-decoders, each disposed between  
7 the cell plates of one of the plurality of pairs;

8       a plurality of Y-select circuits, each disposed  
9 between an inner side of the cell plates of one of the  
10 plurality of pairs and the adjacent sense amplifier of  
11 one of the amplifier columns; and

12       a plurality of X-predecoders, each disposed  
13 adjacent an outer side of the cell plates of one of the  
14 plurality of pairs.

1   10. The semiconductor memory device as claimed in claim  
2 1 or 2, wherein the memory cell array includes a plurality  
3 of horizontal digit lines, and a plurality of vertical  
4 word lines.